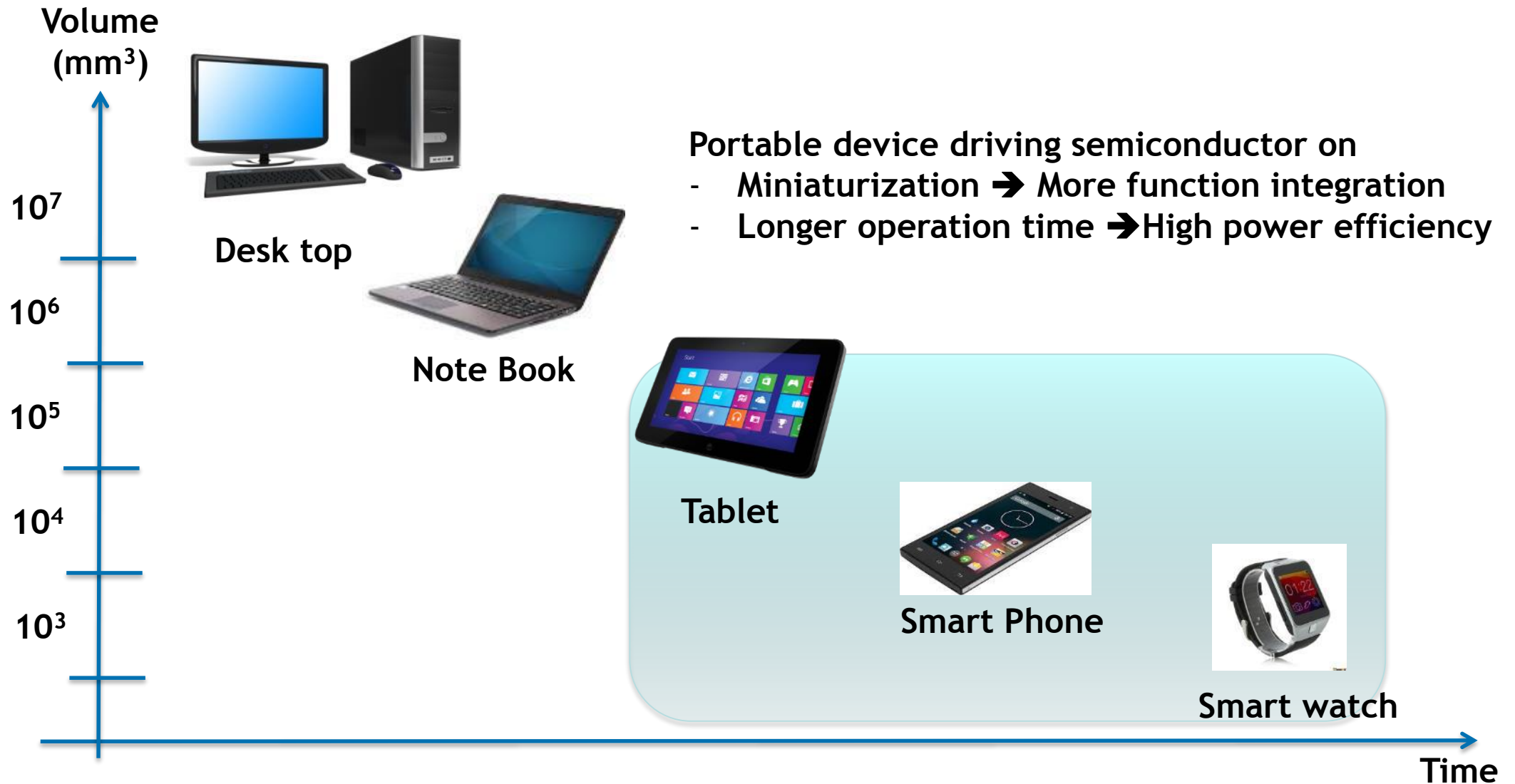


# Innovations in Chip Embedding for Power Packaging



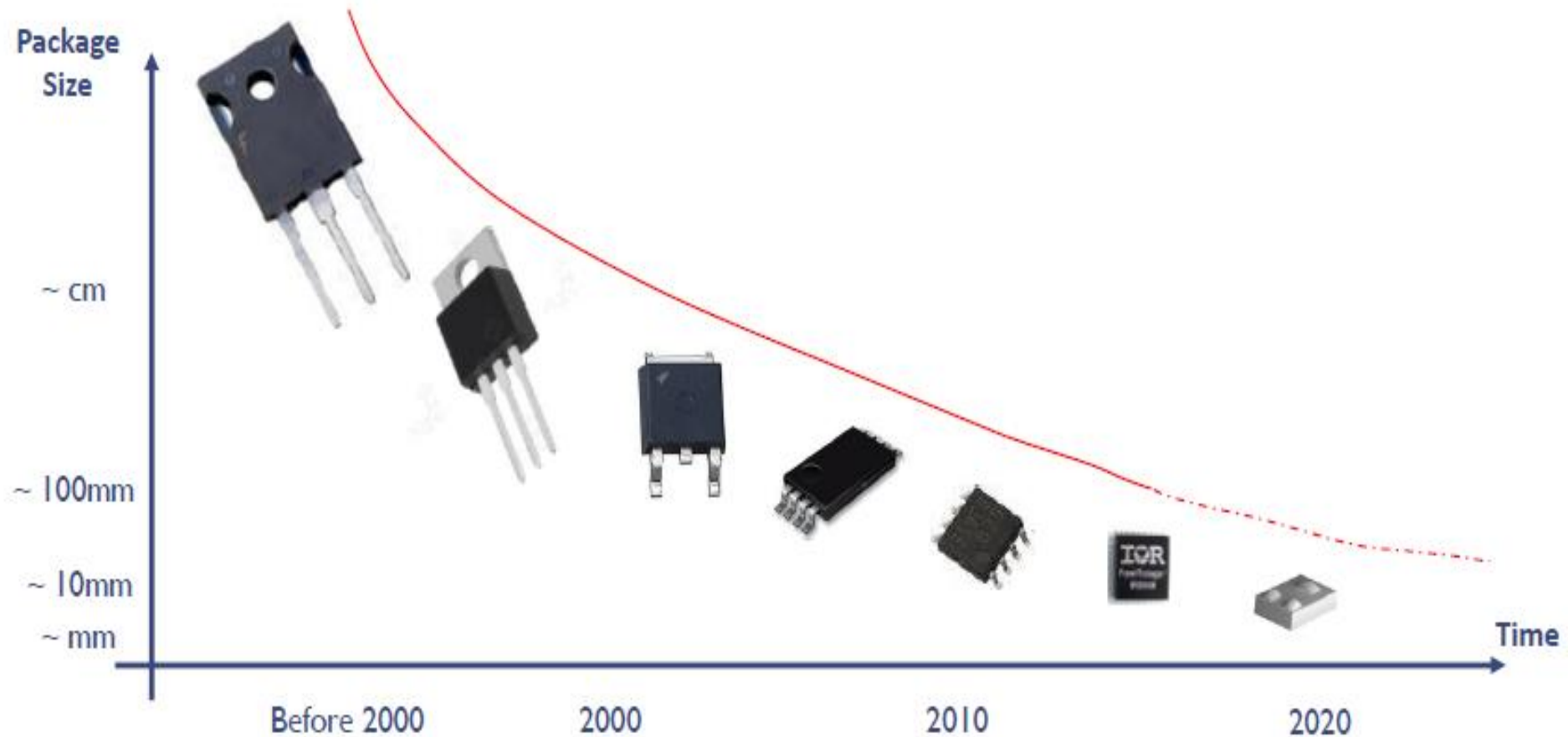
ASE  
Nov, 2016

# Device continue the way to Miniaturization



# Package Solution to Support Miniaturization

## - Power Device Packaging



Source: Yole

# The Evolution Cycle & Challenge



- Higher switching frequency (IC/Wafer design Evolution)



- Smaller Capacitor/inductor
- Light weight
- Small form factor in module/package



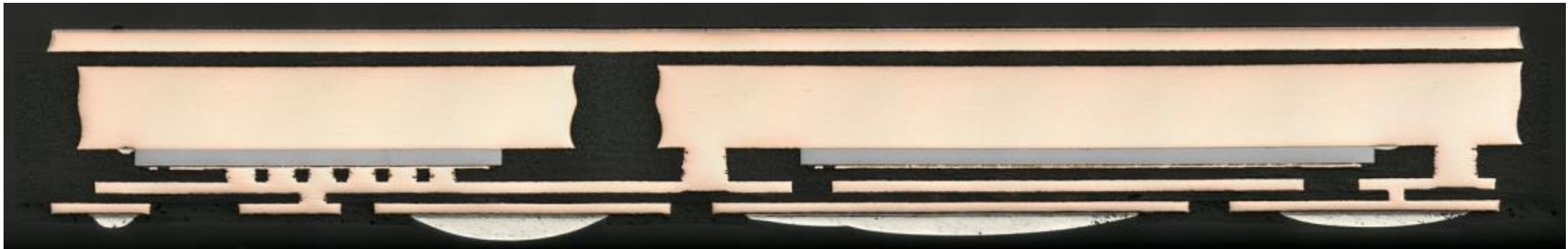
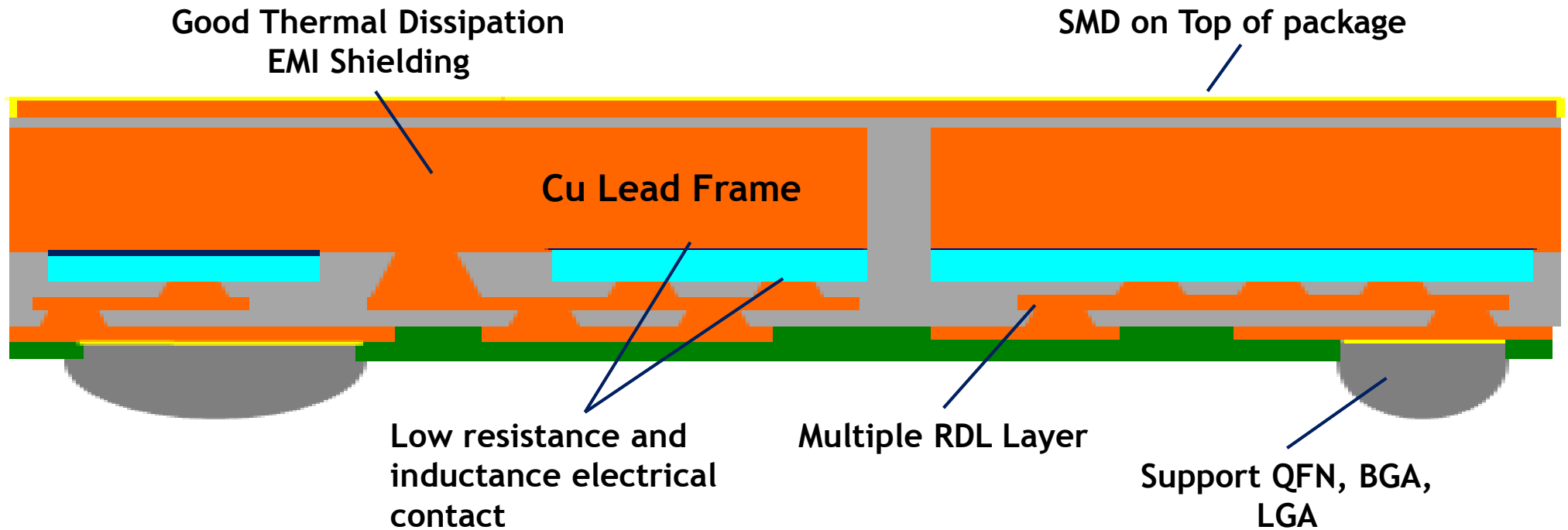
Challenge to Package and system

- Higher current density
- High thermal requirement
- Low package parasitic
- High reliable material
- EMI interference
- Passives integration

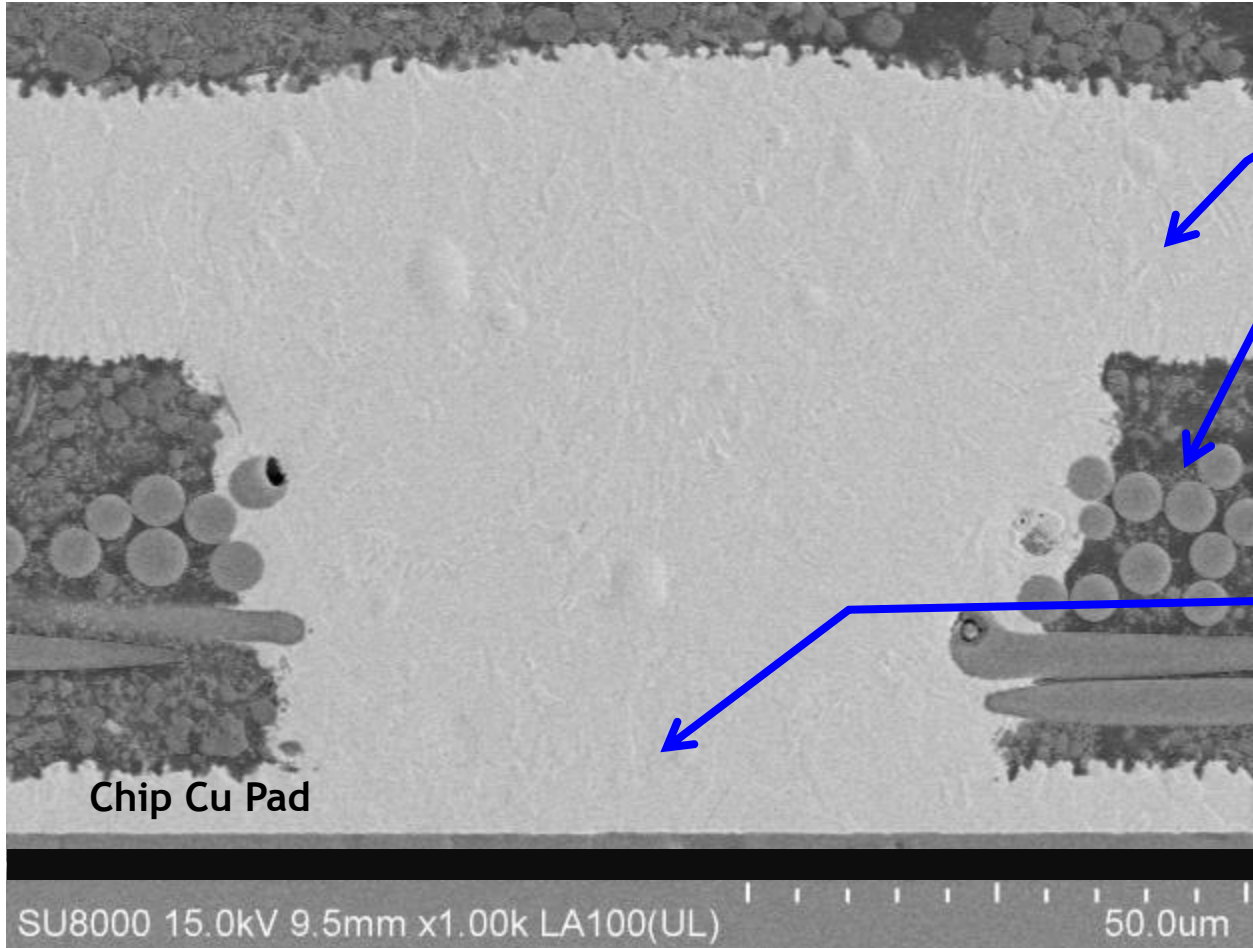


# Package innovation for Power SiP

## - Chip Embedded Technology, aEASI



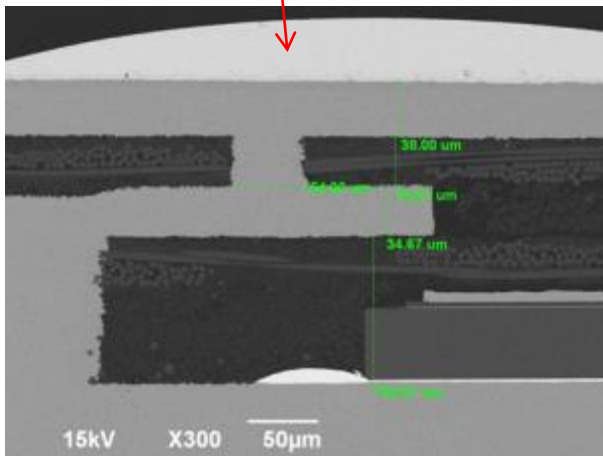
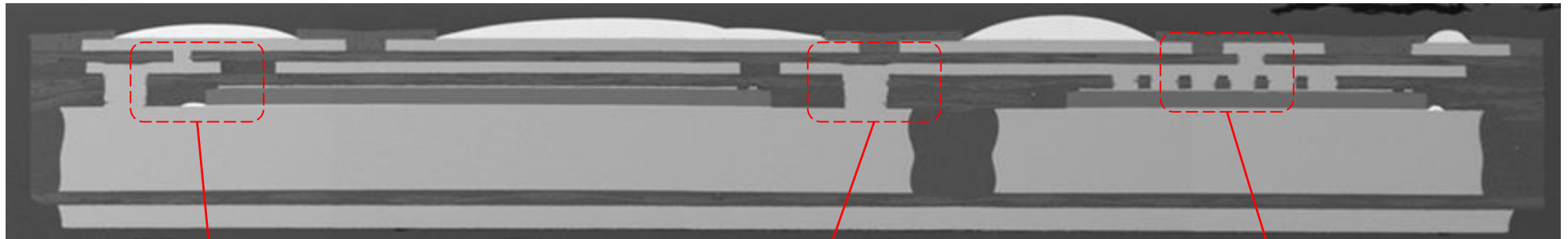
# Die-to-Package Interconnection



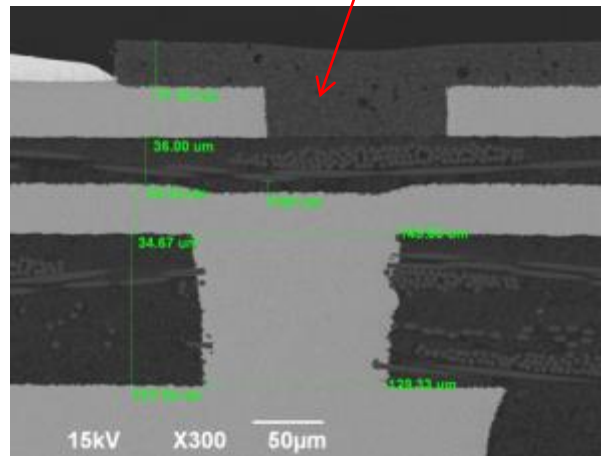
- Thick Cu RDL (32 um).  
Minimize turn on resistance.
- Prepreg material provide  
>2.5KV breakdown voltage  
>230°C (Tg)
- 50um via diameter (Equal  
to Four 1 mil wire bond in  
conductor area)
- Cu to Cu interface.  
Minimize reliability risk in  
high current density  
condition



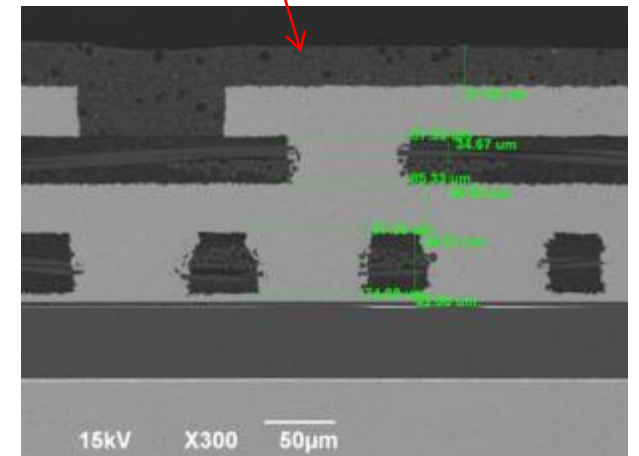
# aEASI P1



**Thick Cu RDL (32um)**



**Deep Via (Diameter = 120um)**

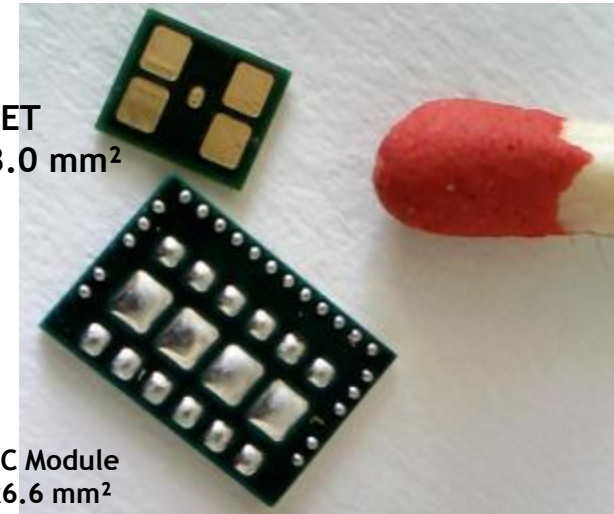


**Small via (Diameter = 70um)  
Thin Die (60um)**

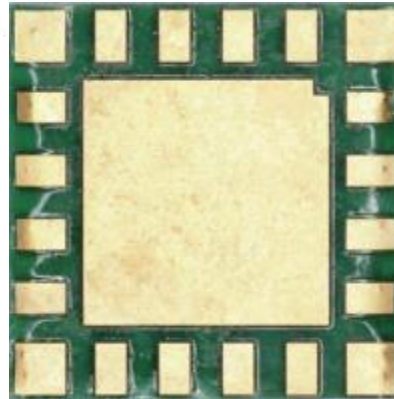
# Power SiP Device - realized by aEASI



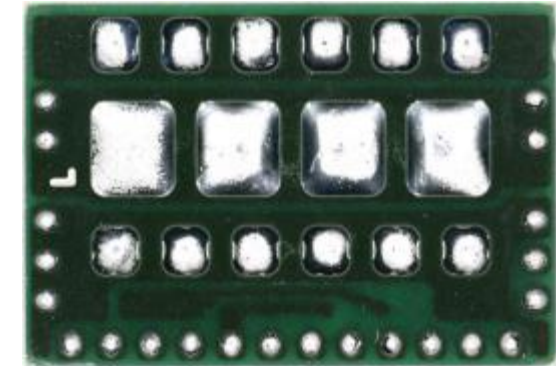
MOSFET  
3.4x3.0 mm<sup>2</sup>



DC/DC Module  
4.5x6.6 mm<sup>2</sup>



Package Size: 5 x 5 x 0.57 mm (exclude passives height)  
1 Micro Power Management Chip  
Passives: 12pc  
0806 x 2, 0603 x 2, 0402 x 4, 0201 x 4  
RDL: 2+1 Layer



Package Size: 6.65 x 4.55 x 0.8 mm  
2 power MOSFET + 1 Driver  
RDL: 2+1 Layer

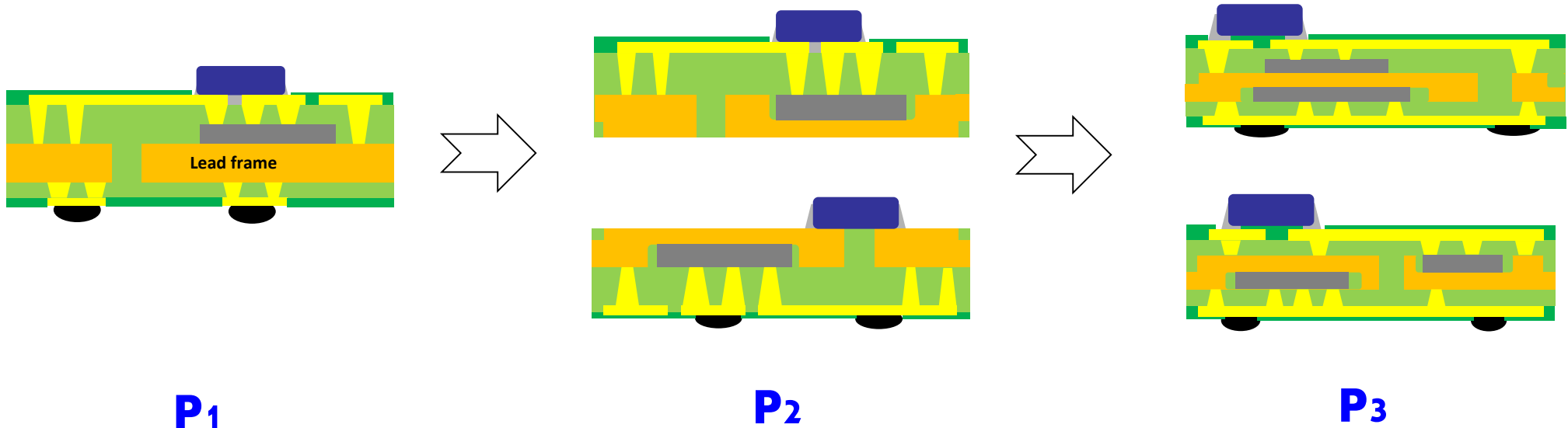


# Continuous Innovation

- Excellent Electrical & Thermal performance
- HVM Production proven

- Thermal Enhance (Exposed pad)
- Thinner Package
- Support various footprint (BGA, LGA, QFN\_

- Improve design flexibility for vertical current device.
- Highly Integration – Smaller form factor



# aEASI P2



Die attach

Lamination

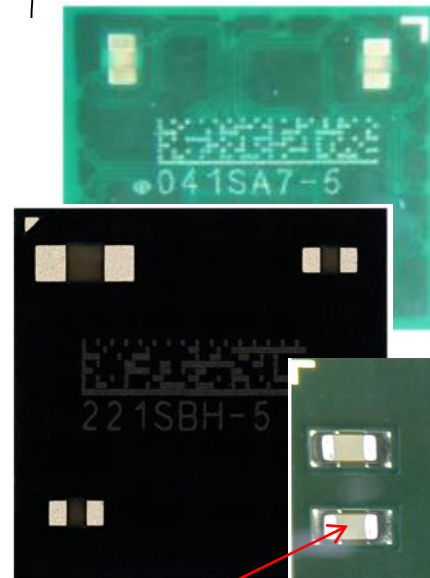
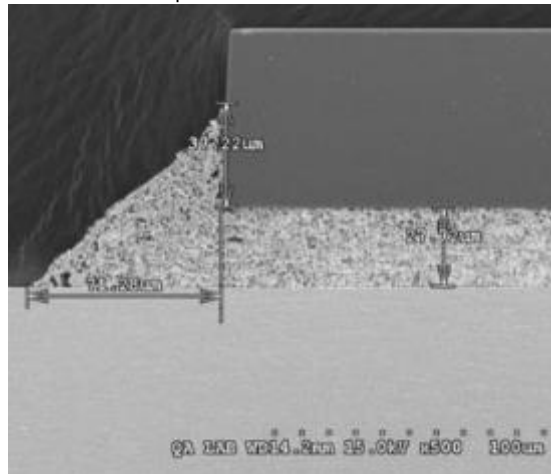
Laser drill

Plating & Patterning

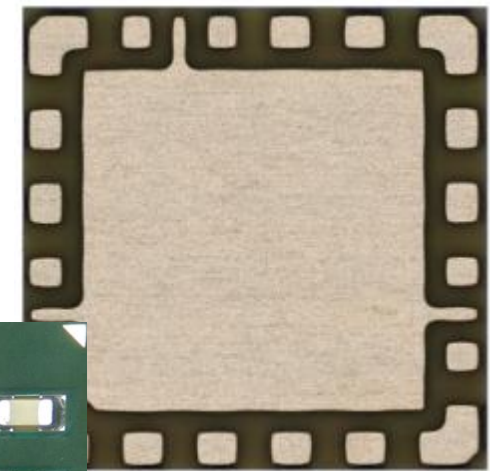
S/M, Marking, Singulation



Ag Sintering

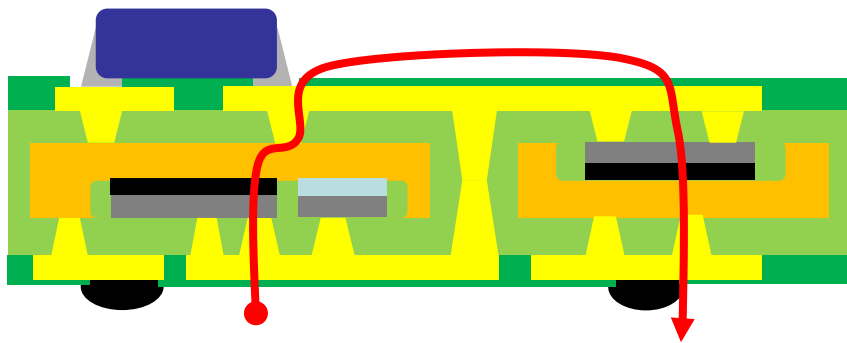


Passives

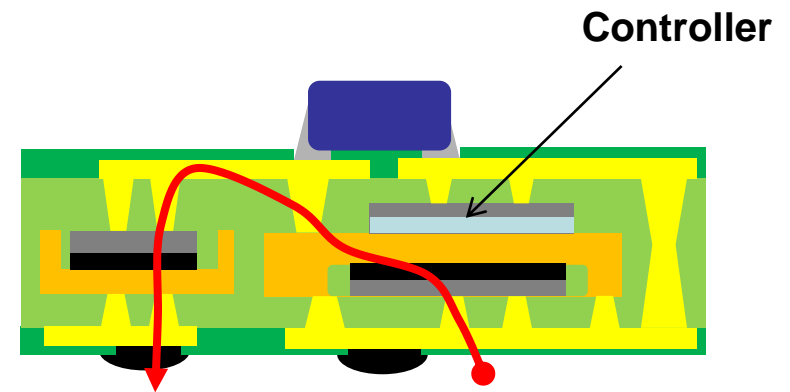


Bottom View

# aEASI P3



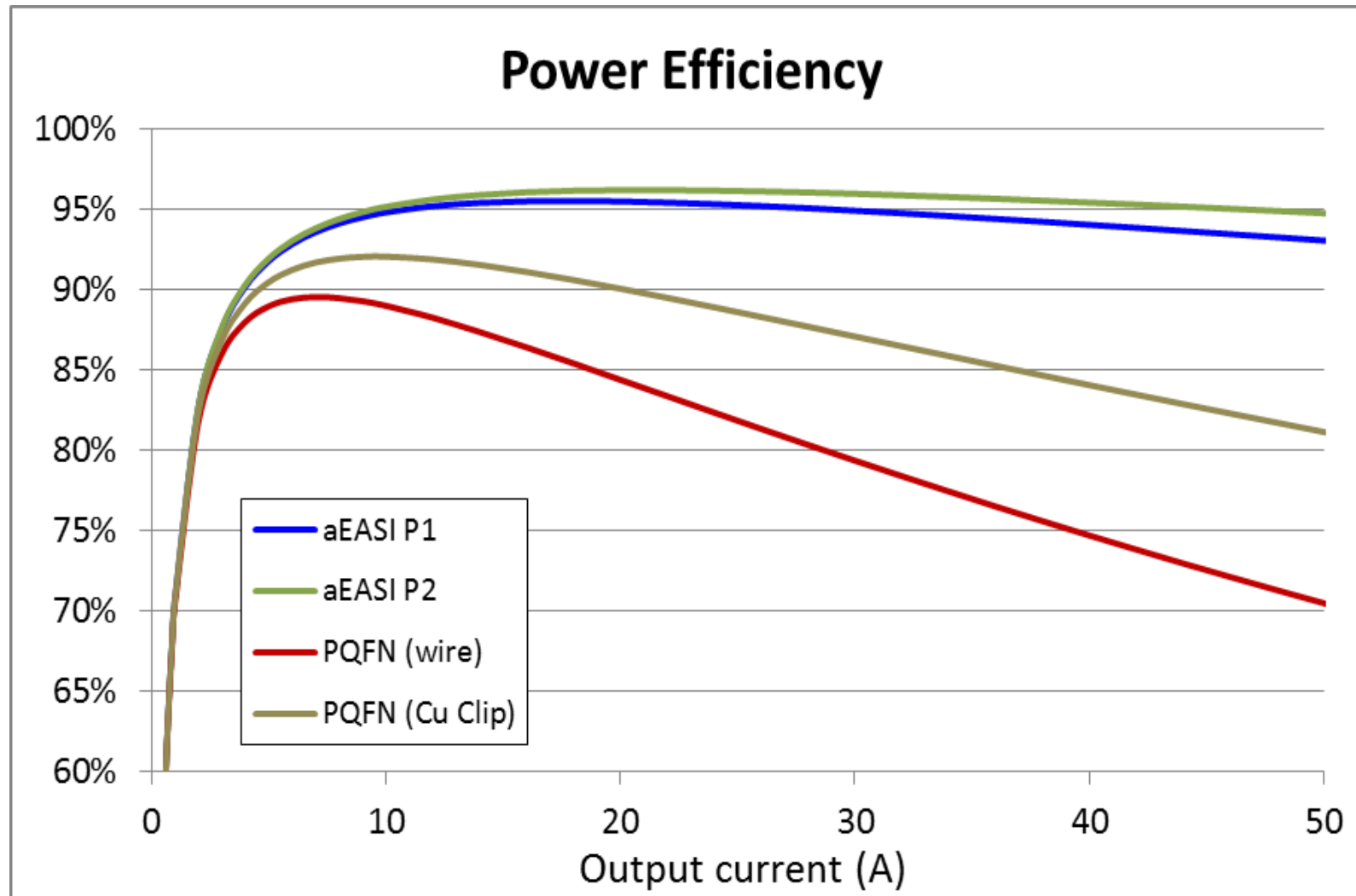
**P<sub>3</sub>**



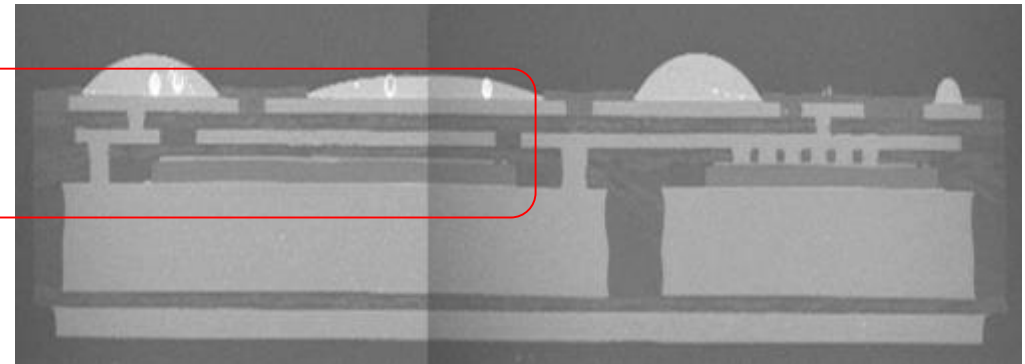
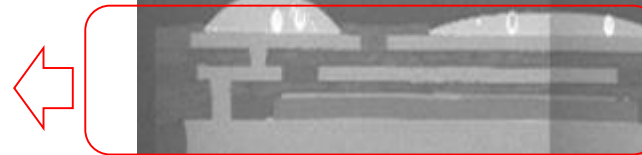
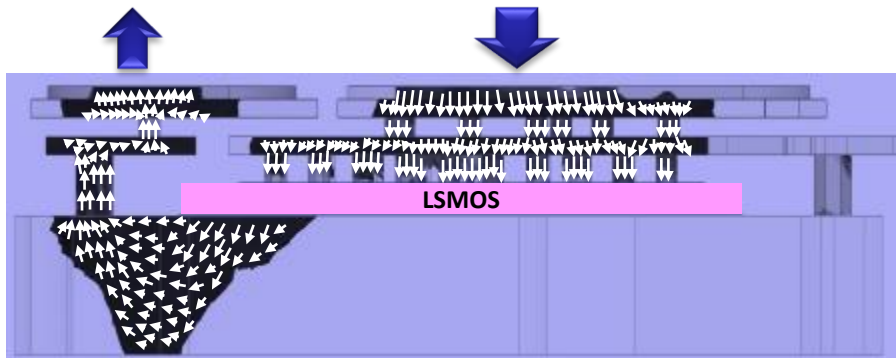
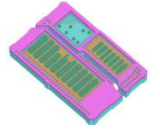
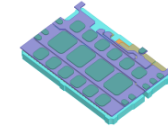
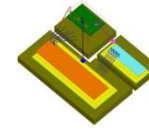
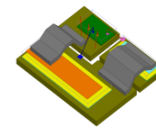
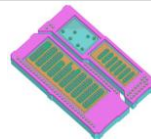
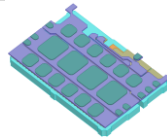
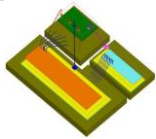
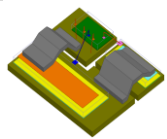
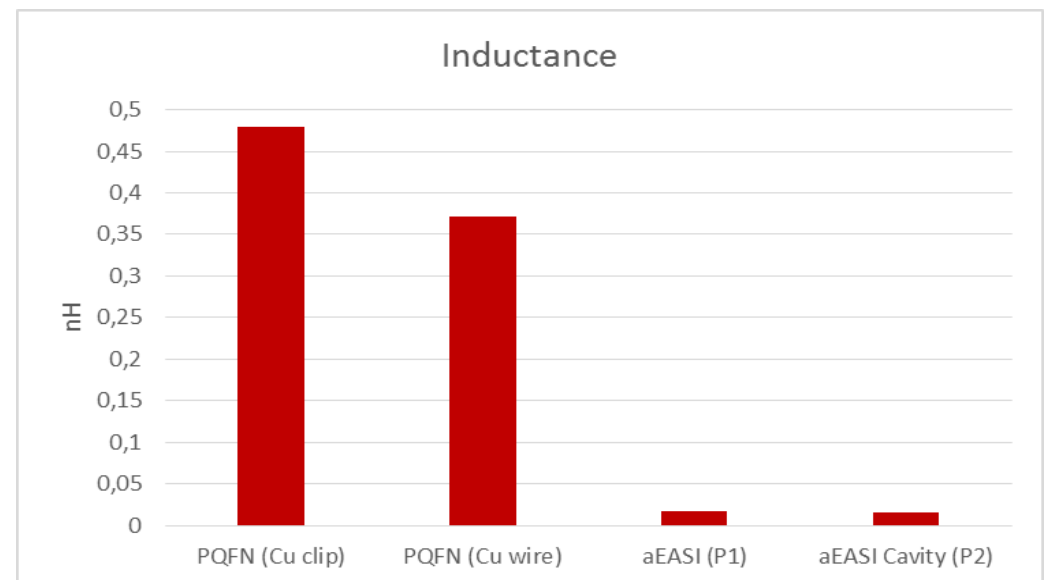
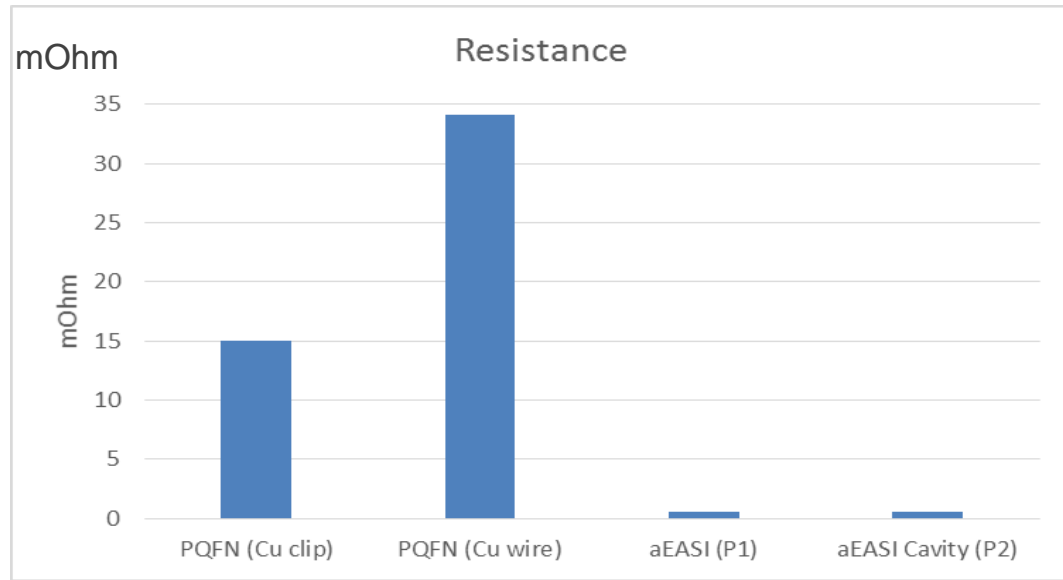
**P<sub>3</sub> – Stack**  
(3D stacking in Chip Embedded Structure)



# Power Conversion Efficiency



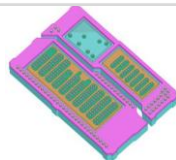
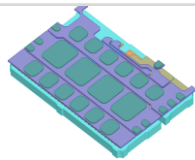
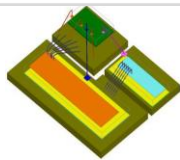
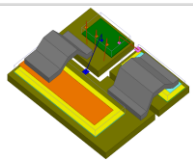
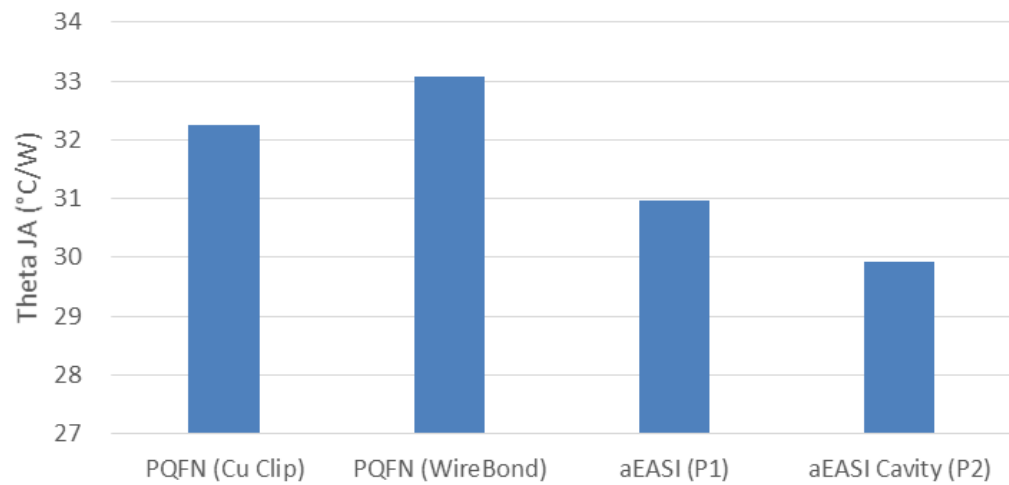
# Packaging Parasitic Resistance & Inductance



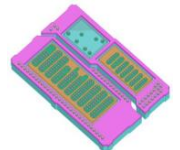
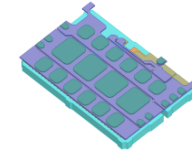
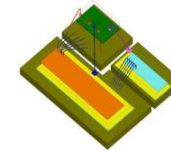
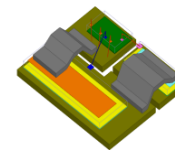
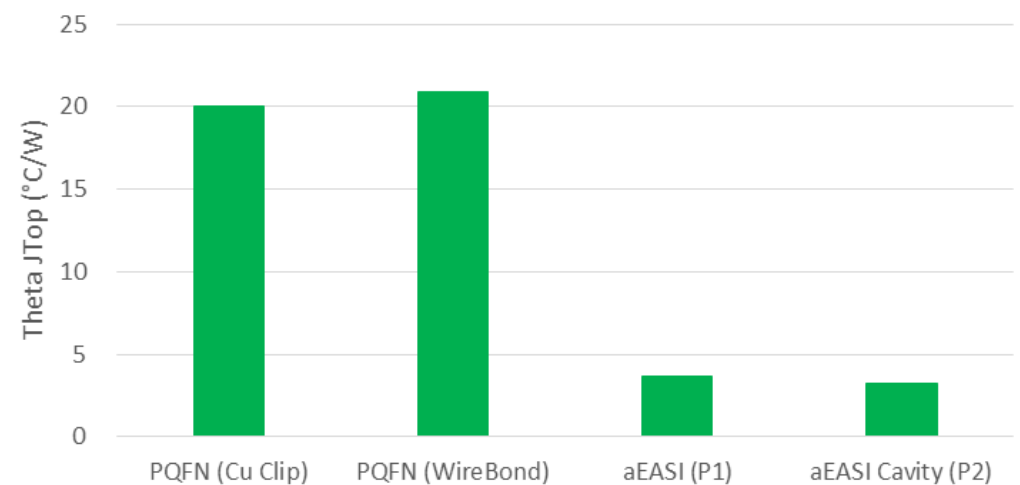


# Thermal Resistance

Thermal Performance  
Theta Ja simulated



Thermal Performance  
Theta JTop Data Sheets



# Summary

- **Advance power device are highly demanding on high switching frequency, higher power efficiency, highly integration and smaller form factor**
- **Chip embedded technology now full fill the requirement with proven high volume production record.**
  - Smaller form factor
  - Passives integration
  - Excellent Electrical & Thermal performance
  - EMI shielding
  - Good Reliability performance



# Thank you

